

PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Appl. No.:	10/565,034	Confirmation No.:	7151
Applicant(s):	Jean-Luc ROUVIERE, et al.		
Filed:	June 8, 2006		
Art Unit:	2855		
Examiner:	Max H. NOORI		
Title:	METHOD FOR MEASURING PHYSICAL PARAMETERS OF AT LEAST ONE MICROMETRIC OR NANOMETRIC DIMENSIONAL PHASE IN A COMPOSITE SYSTEM		

Docket No.: 033339/306516
Customer No.: 00826

Mail Stop Amendment
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

AMENDMENT UNDER 37 C.F.R. § 1.121

Sir:

In response to the Office Action dated November 9, 2007, please amend the above-identified application as follows:

Amendments to the Claims are reflected in the listing of claims beginning on page 2 of this paper.

Remarks/Arguments begin on page 9 of this paper.